Notice of References Cited

Application/Control No.

10/002,864

Examiner

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Applicant(s)/Patent Under
Reexamination
HOFFMANN ET AL.

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,139,955	08-1992	Scholz, Eugen	205/788
	В	US-4,851,352	07-1989	Fischer et al.	436/42
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R				· · · · · · · · · · · · · · · · · · ·	
	S					
	Т					

NON-PATENT DOCUMENTS

*	ļ . <u>.</u> _	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Sherman et al. "Stoichometry and chemical metrology: Karl Fischer reagent; Accreditation and Quality Assurance, May 1999, v. 4, No. 6, pp. 230-234, Abstract and tecxt search from Google (see page link below)				
	\ <u>\</u>	http://www.springerlink.com/app/home/contribution.asp?wasp=d48072eewh4uvl493q7p&referrer=parent&backto=issue,6,16;jour nal,53,83;linkingpublicationresults,1:100393,1				
	w					
	х					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.